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PATENT
Docket No.: 12219/6

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



APPLICANTS: Hiroyuki NISHIDA
SERIAL NO. : Unassigned
FILED : February 26, 2002
FOR : WAVEFRONT MEASURING APPARATUS AND WAVEFRONT
MEASURING METHOD

ASSISTANT COMMISSIONER
FOR PATENTS
Washington D.C. 20231

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97

S I R:


In conformance with Applicants' duty of disclosure under 37 CFR §1.56(a) and §1.97(b), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

In compliance with 37 C.F.R. §1.98, copies of the references are submitted herewith.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,

Date: February 26, 2002


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INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 12219/6	SERIAL NO. Unassigned
	APPLICANT Hir yuki NISHIDA	
	FILING DATE February 26, 2002	GROUP Unassigned

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U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS/ SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION	
					YES	NO
	09-184787	07/15/97	Japan		ABS	
	10-090113	04/10/98	Japan		ABS	

OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.

EXAMINER	DATE CONSIDERED
<p>EXAMINER: Initial if citation is considered, whether or not citation is in conformance with M.P.E.P. 609; strike out citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	